

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re New Patent Application of)
Tatsuya HONDA) Attn: Applications
Japanese Priority Application Nos. 2002-324460) Branch
and 2002-340069)
Japanese Priority Dates: 11/07/2002 & 11/22/2002) Date: November 5, 2003

For: EVALUATION METHOD OF SEMICONDUCTOR DEVICE, MANUFACTURING METHOD OF
THE SEMICONDUCTOR DEVICE, DESIGN MANAGEMENT SYSTEM OF DEVICE COMPRISING
THE SEMICONDUCTOR DEVICE, DOSE AMOUNT CONTROL PROGRAM FOR THE
SEMICONDUCTOR DEVICE, COMPUTER-READABLE RECORDING MEDIUM RECORDING THE
PROGRAM, AND DOSE AMOUNT CONTROL APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

Japanese Patent Application Laid-Open No. 07-66258 is in the same family as U.S. Patent Nos. 5,442,174; 5,502,305; and 5,521,377.

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested

that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

By: 

Jeffrey L. Costellia
Registration No. 35,483

NIXON PEABODY LLP
401 9th Street, N.W.
Suite 900
Washington, D.C. 20004-2128
(202) 585-8000

Substitute for form 1449A/PTO				Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number		New Application
				Filing Date		November 5, 2003
				First Named Inventor		Tatsuya HONDA
				Art Unit		
				Examiner Name		
Sheet	1	of	1	Attorney Docket Number		740756-2664

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
		US-5,442,174	08/15/1995	Kataoka et al.	
		US-5,502,305	03/26/1996	Kataoka	
		US-5,521,377	05/28/1996	Kataoka et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ² (if known)				
		JP 07-66258	03/10/1995	Kataoka et al.		Abstract

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Wen-Chin LEE et al., "Observation of Reduced Poly-Gate Depletion Effect for Poly-Si _{0.8} Ge _{0.2} -Gated NMOS Devices", Electrochemical and Solid-State Letter, 1(1), 1998, pp. 58-59.	
		C.J. KANG et al., "Charge trap dynamics in a SiO ₂ layer on Si by scanning capacitance microscopy", Applied Physics Letters Vol. 74, No. 13, March 29, 1999, pp. 1815-1817.	

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.